

Superconducting Nanowire Single Photon Detector Integrated with optical cavity on Au Reflector

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Abstract

Superconducting nanowire single photon detectors with an optical resonant cavity structure are fabricated directly on the single crystal SiO₂ substrate. In order to enhance the photons absorption of incident light and improve system detection efficiency (SDE) efficiently, the structure of SNSPD with Au mirror on SiO₂ substrate was designed and optimized by the finite-difference time-domain analysis. We obtained an optimized thickness of cavity Si_3N_4 and fabricated the NbN-SNSPD. Measurement of SDE under free space coupling shows saturated detection efficiency at the wavelength of 1064nm by illuminating from the front-side of the device through single mode optical fiber.

0. Background and Motivation

3. Fabrication and measurement Development of superconducting material and fabrication process focus on mechanism to Fabrication: improve SDE, but effective absorption of material depends on the incidence and structure of the cavity largely. Most of the SNSPDs are made on Si substrates, but backside illumination cannot meet the application requirement of wavelengths less than 1000nm because of great UV lithography+Sputtering(Au) loss of Si. Therefore, frontal illumination cavity structure is an ideal choice for all wavelengths. Aiming to design an optical cavity, NIST fabricated WSi-SNSPD by Au mirror and 93% PECVD(SiO₂+SI₃N₄) SDE is obtained at 1550nm, and SIMIT prepared NbN-SNSPD with SDE approximately 80% for wavelength from visible to near infrared using Distributed Brag Reflector. Both of Au mirror and DBR are characterized high reflection performance, and they agreed to adopt DC film deposition (Sputtering) frontal illumination to improve absorption efficiency. Here we introduced fabrication of NbN-SNSPD containing Au mirror and measured the SDE in far-field way from frontside illumination. UV lithography+Sputtering Au (electrode) Fig.9. Scanning electron microscopy EBL(nanowire)+RIE image of nanowire with 100nm width DRD Fig.8. Details of Fabrication Process Si/MgO Fig.1. Diagram showing tungsten silicide layer in red @NIST Fig.2. DBR optical structure for SNSPD@SIMIT 4. Results 1. Device design and simulation S um SiO, substra tins). Oscilloscope persistence map and a recovery Fig.11 Fig.10. I-V characteristics of SSPD@2.2K time constant of approximately 16.8 ns 200 nm Au 00 um SiO, su ÷ Fig.3. Schematic of SNSPD with an optical cavity Fig.4. Calculated optical absorptance at 1064nm for parallel and perpendicular polarizations on Au mirror L_ (µA) Fig.12. Detection response counts@2.2K Fig.13. Dark Count Rate of SNSPD@2.2K 2. Structure and characterization Conclusions 1. We designed NbN-SNSPD with optical cavity by $\mathrm{Si_3N_4}$ on Au mirror and fabricated device at wavelength of 1064nm. 2. We measured the reflectance of Au mirror, Si₂N₄ on Au mirror. Measurement results show that 254) 200 150 97 -96 -95 -94 -93 their reflectance spectra cover the near-infrared band and a high reflectivity is obtained. 3. The chart of AFM show the root mean square (RMS) roughness of Au mirror is 0.67nm and Si_3N_4 on Au is 0.8nm. 14 16 18 20 22 24 26 28 1200 1300 1400 1500 1600 1700 1800 4. We observed oscilloscope persistence map of the response at a bias current of 13 μA and a Fig.5. Superconducting transition temperature of NbN film Fig.6. Reflection spectrum of Au mirror recovery time constant of approximately 16.8ns. and cavity on Au mirror 5. We measured the photon response counts of the device at Gifford-McMahon cryocooler in far field way from front-side illumination. The device presents a saturation detection trend in the target wavelength. References [1] F. Marsili et al. "Detecting single infrared photons with 93% system efficiency", Nature Photonics, 7(2013), pp.210-214.

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Fig.7. Atomic force microscopy image of Au mirror and root mean square roughness of Au mirror

